October 2008

**OFET**<sup>™</sup>



# FQB8N60CF 600V N-Channel MOSFET

## Features

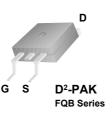
- 6.26A, 600V,  $R_{DS(on)}$  = 1.5  $\Omega$  @V<sub>GS</sub> = 10 V
- Low gate charge (typical 28nC)
- Low Crss (typical 12pF)
- · Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS Compliant

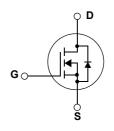


## Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, electronic lamp ballasts based on half bridge topology.





## **Absolute Maximum Ratings**

| Symbol                            | Parameter  | FQB8N60CF   | Units |      |
|-----------------------------------|--|-------------|-------|------|
| V <sub>DSS</sub>                  | Drain-Source Voltage   | 600         | V     |      |
| I <sub>D</sub>                    | Drain Current - Continuous ( $T_C = 25^{\circ}C$ )                           | 6.26        | А     |      |
|                                   | - Continuous (T <sub>C</sub> = 100°C)  | 3.96        | А     |      |
| I <sub>DM</sub>                   | Drain Current - Pulsed   | (Note 1)    | 25    | А    |
| V <sub>GSS</sub>                  | Gate-Source Voltage  |             | ± 30  | V    |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy   | (Note 2)    | 160   | mJ   |
| I <sub>AR</sub>                   | Avalanche Current  | (Note 1)    | 6.26  | А    |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy  | (Note 1)    | 14.7  | mJ   |
| dv/dt                             | Peak Diode Recovery dv/dt  | (Note 3)    | 4.5   | V/ns |
| P <sub>D</sub>                    | Power Dissipation (T <sub>C</sub> = 25°C)                                    |             | 147   | W    |
|                                   | - Derate above 25°C  | 1.18        | W/°C  |      |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Temperature Range                                      | -55 to +150 | °C    |      |
| TL                                | Maximum lead temperature for soldering purposes 1/8" from case for 5 seconds | 300         | °C    |      |

## **Thermal Characteristics**

| Symbol              | Parameter                                | FQB8N60CF | Units |
|---------------------|--|-----------|-------|
| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction-to-Case     | 0.85      | °C/W  |
| $R_{\thetaJA}$      | Thermal Resistance, Junction-to-Ambient* | 40        | °C/W  |
| $R_{\thetaJA}$      | Thermal Resistance, Junction-to-Ambient  | 62.5      | °C/W  |

\* When mounted on the minimum pad size recommended (PCB Mount)

| FQB8N60 |
|---------|
| ĥ       |
| 600V    |
| N-Ch    |
| annel   |
| SOW     |
| Ë       |

| Device Marking Device Packa             |   | Packag  | ge Reel Size Tap                                |  | be Width |           | Quantity |       |      |    |
|---|---|---|---|--|----------|-----------|----------|-------|------|----|
| FQB8N                                   | ·   |   | D2-PAK  | K 330mm  |          |           | 24mm     |       | 800  |    |
|   |   |   |   |  |          |           |          |       |      |    |
| Electric                                | al Chai                                   | racteristics T <sub>c</sub>                             | = 25°C unless other                             | wise noted   |          |           |          |       |      |    |
| Symbol                                  | Parameter                                 |   | Test Conditions                                 |  | Min      | Тур       | Max      | Units |      |    |
| Off Charac                              | teristics                                 |   |   |  |          |           |          |       |      |    |
| BV <sub>DSS</sub>                       | Drain-Source Breakdown Voltage            |   | $V_{GS}$ = 0 V, I <sub>D</sub> = 250 µA         |  |          | 600       |          |       | V    |    |
| ∆BV <sub>DSS</sub> /<br>∆T <sub>J</sub> | Breakdown Voltage Temperature Coefficient |   | $I_D$ = 250 µA, Referenced to 25°C              |  |          |           | 0.7      |       | V/°C |    |
| I <sub>DSS</sub>                        | Zero Gate                                 | ro Gate Voltage Drain Current                           |   | V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V           |          |           |          |       | 10   | μA |
|   |   |   | V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C |  |          |           |          | 100   | μA   |    |
| I <sub>GSSF</sub>                       | Gate-Bod                                  | Gate-Body Leakage Current, Forward V <sub>GS</sub> = 30 |   |  | = 0 V    |           |          |       | 100  | nA |
| I <sub>GSSR</sub>                       | Gate-Bod                                  | Gate-Body Leakage Current, Reverse                      |   | V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V           |          |           |          |       | -100 | nA |
| On Charact                              | eristics                                  |   |   |  |          |           |          |       |      |    |
| V <sub>GS(th)</sub>                     | Gate Threshold Voltage                    |   |   | $V_{DS} = V_{GS}, I_D = 250 \ \mu A$                     |          |           | 2.0      |       | 4.0  | V  |
| R <sub>DS(on)</sub>                     | Static Dra                                | Static Drain-Source On-Resistance                       |   | V <sub>GS</sub> = 10 V, I <sub>D</sub> = 3.13A           |          |           |          | 1.25  | 1.5  | Ω  |
| 9 <sub>FS</sub>                         | Forward Transconductance                  |   |   | V <sub>DS</sub> = 40 V, I <sub>D</sub> = 3.13 A (Note 4) |          |           |          | 8.7   |      | S  |
| Dynamic Cl                              | aracteristi                               | cs  |   |  |          |           |          |       |      |    |
| C <sub>iss</sub>                        | Input Cap                                 | pacitance   | V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,  |  |          |           | 965      | 1255  | pF   |    |
| C <sub>oss</sub>                        | Output Ca                                 | Output Capacitance                                      |   | f = 1.0 MHz  |          |           |          | 105   | 135  | pF |
| C <sub>rss</sub>                        | Reverse Transfer Capacitance              |   |   |  |          |           | 12       | 16    | pF   |    |
| Switching C                             | haracterist                               | tics  |   |  |          |           |          |       |      |    |
| t <sub>d(on)</sub>                      | Turn-On Delay Time                        |   |   | V <sub>DD</sub> = 300 V, I <sub>D</sub> = 6.26A,         |          |           |          | 16.5  | 45   | ns |
| t <sub>r</sub>                          | Turn-On I                                 | Rise Time   |   | R <sub>G</sub> = 25 Ω                                    |          |           |          | 60.5  | 130  | ns |
| t <sub>d(off)</sub>                     | Turn-Off I                                | Delay Time  |   |  |          |           |          | 81    | 170  | ns |
| t <sub>f</sub>                          | Turn-Off I                                | Fall Time   |   |  | (N       | ote 4, 5) |          | 64.5  | 140  | ns |
| Qg                                      | Total Gate                                | e Charge  |   | V <sub>DS</sub> = 480 V, I <sub>D</sub> =                | 6.26A,   |           |          | 28    | 36   | nC |
| Q <sub>gs</sub>                         | Gate-Sou                                  | rce Charge  |   | V <sub>GS</sub> = 10 V                                   |          |           |          | 4.5   |      | nC |
| Q <sub>gd</sub>                         | Gate-Drain Charge (Note                   |   |   | ote 4, 5)  |          | 12        |          | nC    |      |    |
| Drain-Sourc                             | e Diode C                                 | haracteristics and Ma                                   | ximum Ratings                                   |  |          |           |          |       |      |    |
| I <sub>S</sub>                          | Maximum Continuous Drain-Source Diode For |   |   | rward Current  |          |           |          |       | 6.26 | Α  |
| I <sub>SM</sub>                         | Maximum                                   | Pulsed Drain-Source                                     | Diode Forward                                   | d Current  |          |           |          |       | 25   | А  |
| V <sub>SD</sub>                         | Drain-Sou                                 | urce Diode Forward V                                    | oltage  | $V_{GS}$ = 0 V, I <sub>S</sub> = 6.26 A                  |          |           |          |       | 1.4  | V  |
| t <sub>rr</sub>                         | Reverse I                                 | Recovery Time   |   | $V_{GS} = 0 V, I_{S} = 6.$                               |          |           |          | 82    |      | ns |
| Q <sub>rr</sub>                         | Reverse I                                 | Recovery Charge   |   | $dI_{F} / dt = 100 \text{ A}/\mu \text{s}$ (Note 4)      |          | (Note 4)  |          | 242   |      | nC |

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

2. L = 7.3mH, I\_{AS} = 6.26A, V\_DD = 50V, R\_G = 25  $\Omega,$  Starting  $\mbox{ T}_{J}$  = 25°C

3. I\_{SD} \leq 6.26A, di/dt \leq 200A/\mu s, V\_{DD} \leq BV\_{DSS,} Starting  $\ T_{J}$  = 25°C

4. Pulse Test : Pulse width  $\leq 300 \mu s, \, Duty \, cycle \leq 2\%$ 

5. Essentially independent of operating temperature

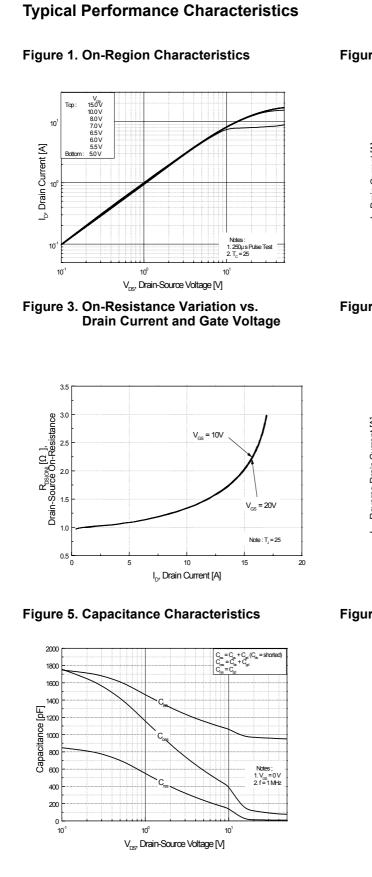
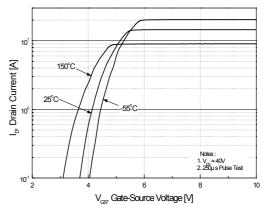
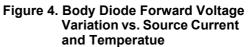


Figure 2. Transfer Characteristics





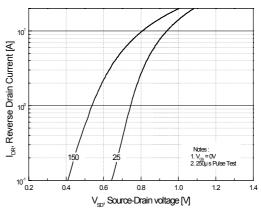
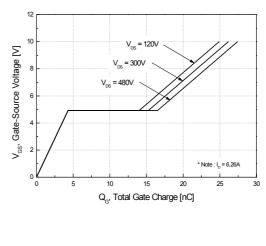
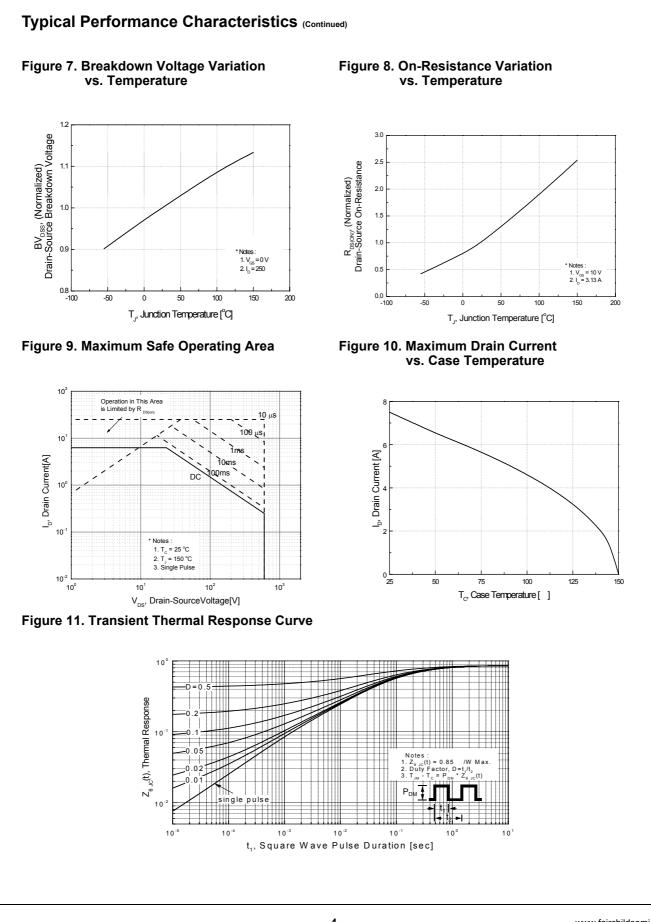
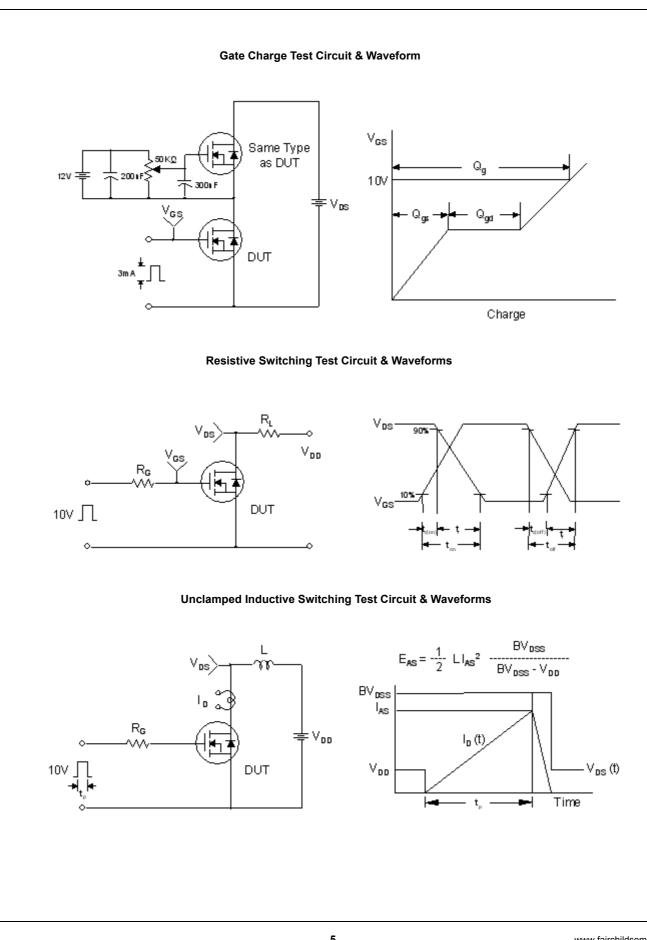
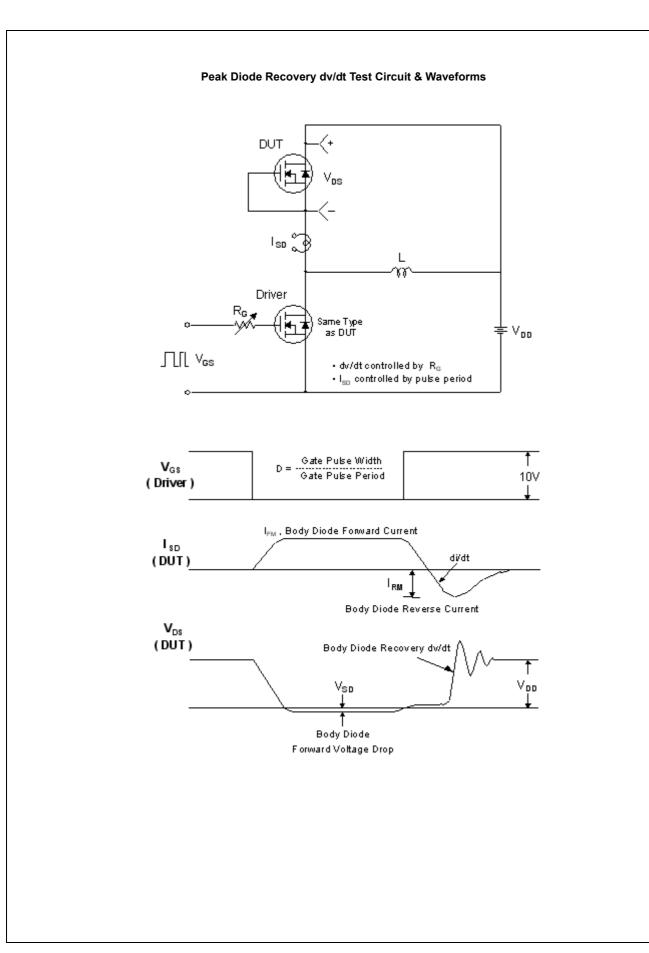


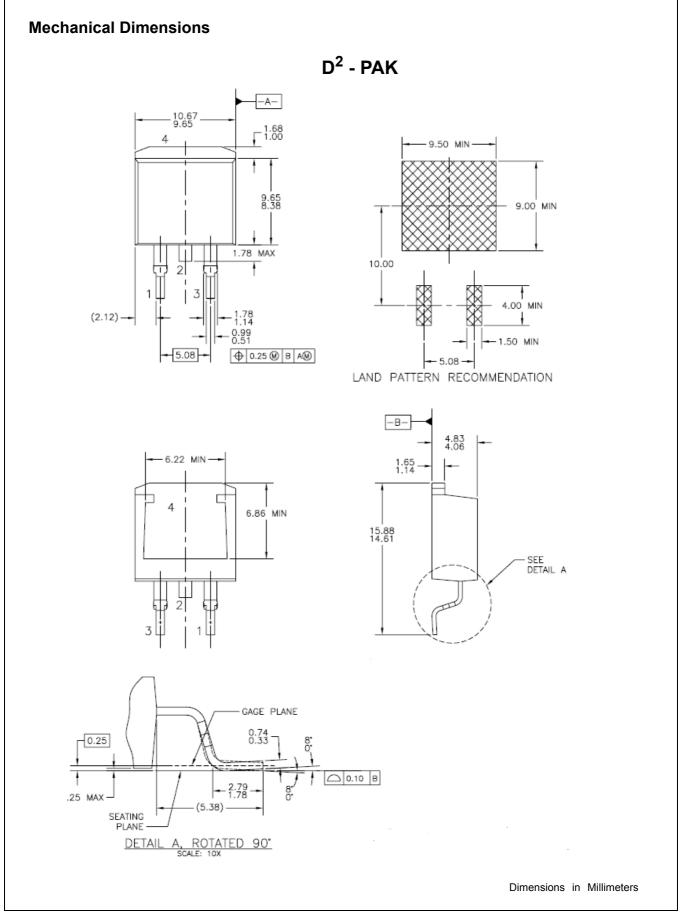
Figure 6. Gate Charge Characteristics













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